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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/603,257	06/26/2003	Yeu Wen Lee	ONS00461	3696

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EXAMINER

STAICOVICI, STEFAN

ART UNIT	PAPER NUMBER
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1732

DATE MAILED: 01/03/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

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Office Action Summary	Application No. 10/603,257	Applicant(s) LEE ET AL.	
	Examiner Stefan Staicovici	Art Unit 1732	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 06 October 2005.
 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-20 is/are pending in the application.
 4a) Of the above claim(s) 17-20 is/are withdrawn from consideration.
 5) ☐ Claim(s) _____ is/are allowed.
 6) ☒ Claim(s) 1-16 is/are rejected.
 7) ☐ Claim(s) _____ is/are objected to.
 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
 10) ☒ The drawing(s) filed on 6/26/03 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
 Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
 Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 a) ☐ All b) ☐ Some * c) ☐ None of:
 1. ☐ Certified copies of the priority documents have been received.
 2. ☐ Certified copies of the priority documents have been received in Application No. _____.
 3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)
Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

Election/Restrictions

1. Applicant's election without traverse of Group I, claims 1-16 in the reply filed on October 6, 2005 is acknowledged.

Claim Rejections - 35 USC § 103

2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 1-16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* US Patent No. 5,766,972).

Applicants' Admitted Prior Art (APA) teaches a process for making a direct chip attach device (DCA) including, attaching (bonding) an electronic chip to a lead-frame structure, placing said DCA device into a mold cavity, injection molding a resin material to encapsulate said DCA device, removing said encapsulated DCA device and forming openings at selected locations to expose contact areas where solder balls are then attached (see paragraph [0008]). Further, Applicants' Admitted Prior Art (APA) teaches the use of bonding pads to attach conductive balls or bumps to said DCA (see paragraph [0002]).

Regarding claims 1-2, 7 and 9, Applicants' Admitted Prior Art (APA) does not teach that said mold has a blocking device, such as a pin, that contacts said conductive bump and that upon

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injection molding openings are formed in the encapsulating material. JP 2001-230520 teaches an injection molding process for making a plurality of openings and through-holes at selected locations of a resulting molded article by using a mold having a plurality of protrusions (11) and pins (12) (see Abstract and, Figures 1b and 1c). Takahashi *et al.* ('972) teach a process for encapsulating a semiconductor device including, attaching (bonding) conductive bumps (30a) using bonding pads (31) to a chip structure (30) to form a semiconductor assembly (DCA), placing said DCA device into a mold cavity such that the top surface said conductive bumps (30a) are flush with said mold surface, applying pressure to maintain full contact at the interface between said mold and said conductive bumps (30a), injection molding a resin material to encapsulate said DCA device and also form openings where said conductive bumps are present in order for solder balls (30b) to be attached (see col. 8, line 59 through col. 9, line 48 and Figures 8-11). Therefore, in view of the teachings of Takahashi *et al.* ('972) showing a desirability to form openings where said conductive bumps are present, it would have been obvious for one of ordinary skill in the art to have provided a mold having a plurality of protrusions and pins as taught by JP 2001-230520 in the process of Applicants' Admitted Prior Art (APA) because, Takahashi *et al.* ('972) specifically teach a desirability to form openings where said conductive bumps are present without the need of an extra step of removing resin material, hence providing for an improved process.

In regard to claims 3 and 14, although Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) do not specifically teach a gold conductive bump, the use of gold in making conductive bumps for DCA device is well known. Therefore, it would have been obvious for one of ordinary skill in the art to have provided a gold

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conductive bump in the DCA device obtained by the process of Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) because of known advantages that gold provides such as increased conductivity and workability and also, because of its well known status.

Specifically regarding claims 4 and 8, Applicants' Admitted Prior Art (APA) teaches the use of bonding pads to attach conductive balls or bumps to said DCA device (see paragraph [0002]) and subsequently attaching solder balls to said conductive balls or bumps through said openings.

Regarding claims 5 and 10, Takahashi *et al.* ('972) teach that conductive bumps of a DCA device have chamfered edges and a flat surface. It is noted that JP 2001-230520 teaches protrusions that have a flat surface (see Figure 1b). Therefore, in view of Takahashi *et al.* ('972) teaching that conductive bumps of a DCA device have chamfered edges and a flat surface, it would have been obvious for one of ordinary skill in the art to have provided pins having chamfered edges and a flat surface in the process of Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) because of the known principle that the mold surface must match the surface of the molded article, hence only pins having chamfered edges and a flat surface are able to form openings that are complementary to conductive bumps having chamfered edges and a flat surface and as such for the invention of Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) to function as described.

In regard to claims 6 and 13, although Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) teach a DCA device, Applicants'

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Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) do not specifically teach a MOSFET device. However, it is well known that a MOSFET device is a DCA device. Therefore, it would have been obvious for one of ordinary skill in the art to have provided a MOSFET device as a DCA device in the process of Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) because it is known that that a MOSFET device is a DCA device, whereas Applicants' Admitted Prior Art (APA) specifically teaches a DCA device.

Specifically regarding claims 11-12 and 15-16, although Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) teach a lead-frame structure, Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) do not specifically teach a flag portion. However, the use of a flag portion during packaging of a semiconductor device is well known. It would have been obvious for one of ordinary skill in the art to have provided a flag portion to the DCA device obtained in the process of Applicants' Admitted Prior Art (APA) in view of JP 2001-230520 and in further view of Takahashi *et al.* ('972) because of known requirements of further attaching a microelectronic device, hence providing an improved product and also because of its known status.

Conclusion

4. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

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5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stefan Staicovici, Ph.D. whose telephone number is (571) 272-1208. The examiner can normally be reached on Monday-Friday 9:30 AM to 6:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael P. Colaianni, can be reached on (571) 272-1196. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Stefan Staicovici, PhD


Primary Examiner

12/23/05

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December 23, 2005